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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	37
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p40l1cefbr

Contents

1	Introduction	7
1.1	Document overview	7
1.2	Description	7
1.3	Device comparison	7
1.4	Block diagram	9
1.5	Feature details	13
1.5.1	High performance e200z0 core processor	13
1.5.2	Crossbar switch (XBAR)	13
1.5.3	Enhanced direct memory access (eDMA)	14
1.5.4	Flash memory	14
1.5.5	Static random access memory (SRAM)	15
1.5.6	Interrupt controller (INTC)	16
1.5.7	System status and configuration module (SSCM)	16
1.5.8	System clocks and clock generation	17
1.5.9	Frequency-modulated phase-locked loop (FMPLL)	17
1.5.10	Main oscillator	17
1.5.11	Internal RC oscillator	17
1.5.12	Periodic interrupt timer (PIT)	18
1.5.13	System timer module (STM)	18
1.5.14	Software watchdog timer (SWT)	18
1.5.15	Fault collection unit (FCU)	18
1.5.16	System integration unit – Lite (SIUL)	19
1.5.17	Boot and censorship	19
1.5.18	Error correction status module (ECSM)	19
1.5.19	Peripheral bridge (PBRIDGE)	20
1.5.20	Controller area network (FlexCAN)	20
1.5.21	Safety port (FlexCAN)	21
1.5.22	Serial communication interface module (LINFlex)	22
1.5.23	Deserial serial peripheral interface (DSPI)	23
1.5.24	Pulse width modulator (FlexPWM)	23
1.5.25	eTimer	25
1.5.26	Analog-to-digital converter (ADC) module	25
1.5.27	Cross triggering unit (CTU)	26
1.5.28	Nexus Development Interface (NDI)	26

List of figures

Figure 1.	Block diagram (SPC560P40 full-featured configuration)	10
Figure 2.	64-pin LQFP pinout – Full featured configuration (top view)	29
Figure 3.	64-pin LQFP pinout – Airbag configuration (top view)	30
Figure 4.	100-pin LQFP pinout – Full featured configuration (top view)	31
Figure 5.	100-pin LQFP pinout – Airbag configuration (top view)	32
Figure 6.	Power supplies constraints ($-0.3 \text{ V} \leq V_{\text{DD_HV_IOx}} \leq 6.0 \text{ V}$)	47
Figure 7.	Independent ADC supply ($-0.3 \text{ V} \leq V_{\text{DD_HV_REG}} \leq 6.0 \text{ V}$)	48
Figure 8.	Power supplies constraints ($3.0 \text{ V} \leq V_{\text{DD_HV_IOx}} \leq 5.5 \text{ V}$)	51
Figure 9.	Independent ADC supply ($3.0 \text{ V} \leq V_{\text{DD_HV_REG}} \leq 5.5 \text{ V}$)	51
Figure 10.	Voltage regulator configuration	55
Figure 11.	Power-up typical sequence	58
Figure 12.	Power-down typical sequence	58
Figure 13.	Brown-out typical sequence	59
Figure 14.	Input DC electrical characteristics definition	63
Figure 15.	ADC characteristics and error definitions	68
Figure 16.	Input equivalent circuit	70
Figure 17.	Transient behavior during sampling phase	70
Figure 18.	Spectral representation of input signal	72
Figure 19.	Pad output delay	77
Figure 20.	Start-up reset requirements	78
Figure 21.	Noise filtering on reset signal	78
Figure 22.	JTAG test clock input timing	80
Figure 23.	JTAG test access port timing	81
Figure 24.	JTAG boundary scan timing	82
Figure 25.	Nexus output timing	83
Figure 26.	Nexus event trigger and test clock timing	83
Figure 27.	Nexus TDI, TMS, TDO timing	84
Figure 28.	External interrupt timing	85
Figure 29.	DSPI classic SPI timing – Master, CPHA = 0	86
Figure 30.	DSPI classic SPI timing – Master, CPHA = 1	87
Figure 31.	DSPI classic SPI timing – Slave, CPHA = 0	87
Figure 32.	DSPI classic SPI timing – Slave, CPHA = 1	88
Figure 33.	DSPI modified transfer format timing – Master, CPHA = 0	88
Figure 34.	DSPI modified transfer format timing – Master, CPHA = 1	89
Figure 35.	DSPI modified transfer format timing – Slave, CPHA = 0	89
Figure 36.	DSPI modified transfer format timing – Slave, CPHA = 1	90
Figure 37.	DSPI PCS Strobe (PCSS) timing	90
Figure 38.	LQFP100 package mechanical drawing	92
Figure 39.	LQFP64 package mechanical drawing	94
Figure 40.	Commercial product code structure	96

Table 4. SPC560P34/SPC560P40 series block summary (continued)

Block	Function
Pulse width modulator (FlexPWM)	Contains four PWM submodules, each of which capable of controlling a single half-bridge power stage and two fault input channels
Reset generation module (MC_RGM)	Centralizes reset sources and manages the device reset sequence of the device
Static random-access memory (SRAM)	Provides storage for program code, constants, and variables
System integration unit lite (SIUL)	Provides control over all the electrical pad controls and up 32 ports with 16 bits of bidirectional, general-purpose input and output signals and supports up to 32 external interrupts with trigger event configuration
System status and configuration module (SSCM)	Provides system configuration and status data (such as memory size and status, device mode and security status), device identification data, debug status port enable and selection, and bus and peripheral abort enable/disable
System timer module (STM)	Provides a set of output compare events to support AUTOSAR ⁽¹⁾ and operating system tasks
System watchdog timer (SWT)	Provides protection from runaway code
Wakeup unit (WKPU)	Supports up to 18 external sources that can generate interrupts or wakeup events, of which 1 can cause non-maskable interrupt requests or wakeup events

1. AUTOSAR: AUTomotive Open System ARchitecture (see www.autosar.org)

1.5 Feature details

1.5.1 High performance e200z0 core processor

The e200z0 Power Architecture core provides the following features:

- High performance e200z0 core processor for managing peripherals and interrupts
- Single issue 4-stage pipeline in-order execution 32-bit Power Architecture CPU
- Harvard architecture
- Variable length encoding (VLE), allowing mixed 16- and 32-bit instructions
 - Results in smaller code size footprint
 - Minimizes impact on performance
- Branch processing acceleration using lookahead instruction buffer
- Load/store unit
 - 1-cycle load latency
 - Misaligned access support
 - No load-to-use pipeline bubbles
- Thirty-two 32-bit general purpose registers (GPRs)
- Separate instruction bus and load/store bus Harvard architecture
- Hardware vectored interrupt support
- Reservation instructions for implementing read-modify-write constructs
- Long cycle time instructions, except for guarded loads, do not increase interrupt latency
- Extensive system development support through Nexus debug port
- Non-maskable interrupt support

1.5.2 Crossbar switch (XBAR)

The XBAR multi-port crossbar switch supports simultaneous connections between three master ports and three slave ports. The crossbar supports a 32-bit address bus width and a 32-bit data bus width.

The crossbar allows for two concurrent transactions to occur from any master port to any slave port; but one of those transfers must be an instruction fetch from internal flash memory. If a slave port is simultaneously requested by more than one master port, arbitration logic will select the higher priority master and grant it ownership of the slave port. All other masters requesting that slave port will be stalled until the higher priority master completes its transactions. Requesting masters will be treated with equal priority and will be granted access a slave port in round-robin fashion, based upon the ID of the last master to be granted access.

The FlexCAN module provides the following features:

- Full implementation of the CAN protocol specification, version 2.0B
 - Standard data and remote frames
 - Extended data and remote frames
 - Up to 8-bytes data length
 - Programmable bit rate up to 1 Mbit/s
- 32 message buffers of up to 8-bytes data length
- Each message buffer configurable as Rx or Tx, all supporting standard and extended messages
- Programmable loop-back mode supporting self-test operation
- 3 programmable mask registers
- Programmable transmit-first scheme: lowest ID or lowest buffer number
- Time stamp based on 16-bit free-running timer
- Global network time, synchronized by a specific message
- Maskable interrupts
- Independent of the transmission medium (an external transceiver is assumed)
- High immunity to EMI
- Short latency time due to an arbitration scheme for high-priority messages
- Transmit features
 - Supports configuration of multiple mailboxes to form message queues of scalable depth
 - Arbitration scheme according to message ID or message buffer number
 - Internal arbitration to guarantee no inner or outer priority inversion
 - Transmit abort procedure and notification
- Receive features
 - Individual programmable filters for each mailbox
 - 8 mailboxes configurable as a 6-entry receive FIFO
 - 8 programmable acceptance filters for receive FIFO
- Programmable clock source
 - System clock
 - Direct oscillator clock to avoid PLL jitter

1.5.21 Safety port (FlexCAN)

The SPC560P34/SPC560P40 MCU has a second CAN controller synthesized to run at high bit rates to be used as a safety port. The CAN module of the safety port provides the following features:

- Identical to the FlexCAN module
- Bit rate up to 8 Mbit/s at 64 MHz CPU clock using direct connection between CAN modules (no physical transceiver required)
- 32 message buffers of up to 8-bytes data length
- Can be used as a second independent CAN module

1.5.22 Serial communication interface module (LINFlex)

The LINFlex (local interconnect network flexible) on the SPC560P34/SPC560P40 features the following:

- Supports LIN Master mode (both instances), LIN Slave mode (only one instance) and UART mode
- LIN state machine compliant to LIN1.3, 2.0 and 2.1 specifications
- Handles LIN frame transmission and reception without CPU intervention
- LIN features
 - Autonomous LIN frame handling
 - Message buffer to store Identifier and up to 8 data bytes
 - Supports message length of up to 64 bytes
 - Detection and flagging of LIN errors (sync field, delimiter, ID parity, bit framing, checksum, and time-out)
 - Classic or extended checksum calculation
 - Configurable Break duration of up to 36-bit times
 - Programmable baud rate prescalers (13-bit mantissa, 4-bit fractional)
 - Diagnostic features: Loop back; Self Test; LIN bus stuck dominant detection
 - Interrupt-driven operation with 16 interrupt sources
- LIN slave mode features:
 - Autonomous LIN header handling
 - Autonomous LIN response handling
 - Optional discarding of irrelevant LIN responses using ID filter
- UART mode:
 - Full-duplex operation
 - Standard non return-to-zero (NRZ) mark/space format
 - Data buffers with 4-byte receive, 4-byte transmit
 - Configurable word length (8-bit or 9-bit words)
 - Error detection and flagging
 - Parity, Noise and Framing errors
 - Interrupt-driven operation with four interrupt sources
 - Separate transmitter and receiver CPU interrupt sources
 - 16-bit programmable baud-rate modulus counter and 16-bit fractional
 - 2 receiver wake-up methods

1.5.23 Deserial serial peripheral interface (DSPI)

The deserial serial peripheral interface (DSPI) module provides a synchronous serial interface for communication between the SPC560P34/SPC560P40 MCU and external devices.

The DSPI modules provide these features:

- Full duplex, synchronous transfers
- Master or slave operation
- Programmable master bit rates
- Programmable clock polarity and phase
- End-of-transmission interrupt flag
- Programmable transfer baud rate
- Programmable data frames from 4 to 16 bits
- Up to 8 chip select lines available:
 - 8 on DSPI_0
 - 4 each on DSPI_1 and DSPI_2
- 8 clock and transfer attributes registers
- Chip select strobe available as alternate function on one of the chip select pins for deglitching
- FIFOs for buffering up to 4 transfers on the transmit and receive side
- Queueing operation possible through use of the I/O processor or eDMA
- General purpose I/O functionality on pins when not used for SPI

1.5.24 Pulse width modulator (FlexPWM)

The pulse width modulator module (PWM) contains four PWM submodules each of which is set up to control a single half-bridge power stage. There are also three fault channels.

This PWM is capable of controlling most motor types: AC induction motors (ACIM), permanent magnet AC motors (PMAC), both brushless (BLDC) and brush DC motors (BDC), switched (SRM) and variable reluctance motors (VRM), and stepper motors.

1.5.25 eTimer

The SPC560P34/SPC560P40 includes one eTimer module which provides six 16-bit general purpose up/down timer/counter units with the following features:

- Clock frequency same as that used for the e200z0h core
- Individual channel capability
 - Input capture trigger
 - Output compare
 - Double buffer (to capture rising edge and falling edge)
 - Separate prescaler for each counter
 - Selectable clock source
 - 0–100% pulse measurement
 - Rotation direction flag (quad decoder mode)
- Maximum count rate
 - External event counting: max. count rate = peripheral clock/2
 - Internal clock counting: max. count rate = peripheral clock
- Counters are:
 - Cascadable
 - Preloadable
- Programmable count modulo
- Quadrature decode capabilities
- Counters can share available input pins
- Count once or repeatedly
- Pins available as GPIO when timer functionality not in use

1.5.26 Analog-to-digital converter (ADC) module

The ADC module provides the following features:

Analog part:

- 1 on-chip analog-to-digital converter
 - 10-bit AD resolution
 - 1 sample and hold unit
 - Conversion time, including sampling time, less than 1 μ s (at full precision)
 - Typical sampling time is 150 ns minimum (at full precision)
 - DNL/INL ± 1 LSB
 - TUE < 1.5 LSB
 - Single-ended input signal up to 3.3 V/5.0 V
 - 3.3 V/5.0 V input reference voltage
 - ADC and its reference can be supplied with a voltage independent from V_{DDIO}
 - ADC supply can be equal or higher than V_{DDIO}
 - ADC supply and ADC reference are not independent from each other (both internally bonded to same pad)
 - Sample times of 2 (default), 8, 64 or 128 ADC clock cycles

Table 7. Pin muxing (continued)

Port pin	PCR register	Alternate function ^{(1),(2)}	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin	
						SRC = 0	SRC = 1	64-pin	100-pin
A[4]	PCR[4]	ALT0 — ALT1 ALT2 ALT3 — —	GPIO[4] — CS1 ETC[4] FAB EIRQ[4]	SIUL — DSPI_2 eTimer_0 MC_RGM SIUL	I/O — O I/O I I	Slow	Medium	48	75
A[5]	PCR[5]	ALT0 ALT1 ALT2 ALT3 —	GPIO[5] CS0 — CS7 EIRQ[5]	SIUL DSPI_1 — DSPI_0 SIUL	I/O I/O — O I	Slow	Medium	5	8
A[6]	PCR[6]	ALT0 ALT1 ALT2 ALT3 —	GPIO[6] SCK — — EIRQ[6]	SIUL DSPI_1 — — SIUL	I/O I/O — — I	Slow	Medium	2	2
A[7]	PCR[7]	ALT0 ALT1 ALT2 ALT3 —	GPIO[7] SOUT — — EIRQ[7]	SIUL DSPI_1 — — SIUL	I/O O — — I	Slow	Medium	3	4
A[8]	PCR[8]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[8] — — — SIN EIRQ[8]	SIUL — — — DSPI_1 SIUL	I/O — — — I I	Slow	Medium	4	6
A[9]	PCR[9]	ALT0 ALT1 ALT2 ALT3 —	GPIO[9] CS1 — B[3] FAULT[0]	SIUL DSPI_2 — FlexPWM_0 FlexPWM_0	I/O O — O I	Slow	Medium	60	94
A[10]	PCR[10]	ALT0 ALT1 ALT2 ALT3 —	GPIO[10] CS0 B[0] X[2] EIRQ[9]	SIUL DSPI_2 FlexPWM_0 FlexPWM_0 SIUL	I/O I/O O O I	Slow	Medium	52	81

Table 7. Pin muxing (continued)

Port pin	PCR register	Alternate function ^{(1),(2)}	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin	
						SRC = 0	SRC = 1	64-pin	100-pin
C[9]	PCR[41]	ALT0 ALT1 ALT2 ALT3	GPIO[41] CS3 — X[3]	SIUL DSPI_2 — FlexPWM_0	I/O O — O	Slow	Medium	—	84
C[10]	PCR[42]	ALT0 ALT1 ALT2 ALT3 —	GPIO[42] CS2 — A[3] FAULT[1]	SIUL DSPI_2 — FlexPWM_0 FlexPWM_0	I/O O — O I	Slow	Medium	—	78
C[11]	PCR[43]	ALT0 ALT1 ALT2 ALT3	GPIO[43] ETC[4] CS2 —	SIUL eTimer_0 DSPI_2 —	I/O I/O O —	Slow	Medium	33	55
C[12]	PCR[44]	ALT0 ALT1 ALT2 ALT3	GPIO[44] ETC[5] CS3 —	SIUL eTimer_0 DSPI_2 —	I/O I/O O —	Slow	Medium	34	56
C[13]	PCR[45]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[45] — — — EXT_IN EXT_SYNC	SIUL — — — CTU_0 FlexPWM_0	I/O — — — I I	Slow	Medium	—	71
C[14]	PCR[46]	ALT0 ALT1 ALT2 ALT3	GPIO[46] — EXT_TGR —	SIUL — CTU_0 —	I/O — O —	Slow	Medium	—	72
C[15]	PCR[47]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[47] — — A[1] EXT_IN EXT_SYNC	SIUL — — FlexPWM_0 CTU_0 FlexPWM_0	I/O — — O I I	Slow	Medium	—	85
Port D (16-bit)									
D[0]	PCR[48]	ALT0 ALT1 ALT2 ALT3	GPIO[48] — — B[1]	SIUL — — FlexPWM_0	I/O — — O	Slow	Medium	—	86

3.8.2 Voltage monitor electrical characteristics

The device implements a power on reset module to ensure correct power-up initialization, as well as three low voltage detectors to monitor the V_{DD} and the V_{DD_LV} voltage while device is supplied:

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply
- LVDHV5 monitors V_{DD} when application uses device in the $5.0\text{ V} \pm 10\%$ range
- LVDLVCOR monitors low voltage digital power domain

Table 17. Low voltage monitor electrical characteristics

Symbol	C	Parameter	Conditions ⁽¹⁾	Value		Unit
				Min	Max	
V_{PORH}	T	Power-on reset threshold	—	1.5	2.7	V
V_{PORUP}	P	Supply for functional POR module	$T_A = 25\text{ }^\circ\text{C}$	1.0	—	V
$V_{REGLVDMOK_H}$	P	Regulator low voltage detector high threshold	—	—	2.95	V
$V_{REGLVDMOK_L}$	P	Regulator low voltage detector low threshold	—	2.6	—	V
$V_{FLLVDMOK_H}$	P	Flash low voltage detector high threshold	—	—	2.95	V
$V_{FLLVDMOK_L}$	P	Flash low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDMOK_H}$	P	I/O low voltage detector high threshold	—	—	2.95	V
$V_{IOLVDMOK_L}$	P	I/O low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDM5OK_H}$	P	I/O 5 V low voltage detector high threshold	—	—	4.4	V
$V_{IOLVDM5OK_L}$	P	I/O 5 V low voltage detector low threshold	—	3.8	—	V
$V_{MLVDDOK_H}$	P	Digital supply low voltage detector high	—	—	1.145	V
$V_{MLVDDOK_L}$	P	Digital supply low voltage detector low	—	1.08	—	V

1. $V_{DD} = 3.3\text{ V} \pm 10\% / 5.0\text{ V} \pm 10\%$, $T_A = -40\text{ }^\circ\text{C}$ to $T_A\text{ MAX}$, unless otherwise specified

3.9 Power up/down sequencing

To prevent an overstress event or a malfunction within and outside the device, the SPC560P34/SPC560P40 implements the following sequence to ensure each module is started only when all conditions for switching it ON are available:

- A POWER_ON module working on voltage regulator supply controls the correct start-up of the regulator. This is a key module ensuring safe configuration for all voltage regulator functionality when supply is below 1.5 V. Associated POWER_ON (or POR) signal is active low.
- Several low voltage detectors, working on voltage regulator supply monitor the voltage of the critical modules (voltage regulator, I/Os, flash memory and low voltage domain). LVDs are gated low when POWER_ON is active.
- A POWER_OK signal is generated when all critical supplies monitored by the LVD are available. This signal is active high and released to all modules including I/Os, flash

3.10.2 DC electrical characteristics (5 V)

Table 19 gives the DC electrical characteristics at 5 V ($4.5 \text{ V} < V_{DD_HV_IOx} < 5.5 \text{ V}$, NVUSRO[PAD3V5V] = 0).

Table 19. DC electrical characteristics (5.0 V, NVUSRO[PAD3V5V] = 0)

Symbol	C	Parameter	Conditions	Value		Unit
				Min	Max	
V_{IL}	D	Low level input voltage	—	-0.4 ⁽¹⁾	—	V
	P		—	—	$0.35 V_{DD_HV_IOx}$	V
V_{IH}	P	High level input voltage	—	$0.65 V_{DD_HV_IOx}$	—	V
	D		—	—	$V_{DD_HV_IOx} + 0.4$ ⁽¹⁾	V
V_{HYS}	T	Schmitt trigger hysteresis	—	$0.1 V_{DD_HV_IOx}$	—	V
V_{OL_S}	P	Slow, low level output voltage	$I_{OL} = 3 \text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_S}	P	Slow, high level output voltage	$I_{OH} = -3 \text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
V_{OL_M}	P	Medium, low level output voltage	$I_{OL} = 3 \text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_M}	P	Medium, high level output voltage	$I_{OH} = -3 \text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
V_{OL_F}	P	Fast, low level output voltage	$I_{OL} = 14 \text{ mA}$	—	$0.1 V_{DD_HV_IOx}$	V
V_{OH_F}	P	Fast, high level output voltage	$I_{OH} = -14 \text{ mA}$	$0.8 V_{DD_HV_IOx}$	—	V
I_{PU}	P	Equivalent pull-up current	$V_{IN} = V_{IL}$	-130	—	μA
			$V_{IN} = V_{IH}$	—	-10	
I_{PD}	P	Equivalent pull-down current	$V_{IN} = V_{IL}$	10	—	μA
			$V_{IN} = V_{IH}$	—	130	
I_{IL}	P	Input leakage current (all bidirectional ports)	$T_A = -40 \text{ to } 125^\circ\text{C}$	-1	1	μA
I_{IL}	P	Input leakage current (all ADC input-only ports)	$T_A = -40 \text{ to } 125^\circ\text{C}$	-0.5	0.5	μA
C_{IN}	D	Input capacitance	—	—	10	pF

1. "SR" parameter values must not exceed the absolute maximum ratings shown in *Table 9*.

Table 24. I/O consumption (continued)

Symbol	C	Parameter	Conditions ⁽¹⁾	Value			Unit	
				Min	Typ	Max		
I _{RMSFST}	C C	Root medium square I/O current for FAST configuration	C _L = 25 pF, 40 MHz	—	—	22	mA	
			C _L = 25 pF, 64 MHz	—	—	33		
			C _L = 100 pF, 40 MHz	—	—	56		
			C _L = 25 pF, 40 MHz	—	—	14		
			C _L = 25 pF, 64 MHz	—	—	20		
			C _L = 100 pF, 40 MHz	—	—	35		
I _{AVGSEG}	S R	D	Sum of all the static I/O current within a supply segment	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	70	mA
				V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	65	

1. V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = -40 to 125 °C, unless otherwise specified

2. Stated maximum values represent peak consumption that lasts only a few ns during I/O transition.

3.11 Main oscillator electrical characteristics

The SPC560P34/SPC560P40 provides an oscillator/resonator driver.

Table 25. Main oscillator output electrical characteristics (5.0 V, NVUSRO[PAD3V5V] = 0)

Symbol	C	Parameter	Conditions	Value		Unit
				Min	Max	
f _{OSC}	SR	—	Oscillator frequency	4	40	MHz
g _m	—	P	Transconductance	6.5	25	mA/V
V _{OSC}	—	T	Oscillation amplitude on XTAL pin	1	—	V
t _{oscsu}	—	T	Start-up time ^{(1),(2)}	8	—	ms
C _L	CC	XTAL load capacitance ⁽³⁾	4 MHz	5	30	pf
			8 MHz	5	26	
			12 MHz	5	23	
			16 MHz	5	19	
			20 MHz	5	16	
			40 MHz	5	8	

1. The start-up time is dependent upon crystal characteristics, board leakage, etc. High ESR and excessive capacitive loads can cause long start-up time.

2. Value captured when amplitude reaches 90% of XTAL

3. This value is determined by the crystal manufacturer and board design. For 4 MHz to 40 MHz crystals specified for this oscillator, load capacitors should not exceed these limits.

Table 28. FMPLL electrical characteristics (continued)

Symbol	C	Parameter	Conditions ⁽¹⁾	Value		Unit
				Min	Max	
f_{FREE}	P	Free-running frequency	Measured using clock division—typically /16	20	150	MHz
t_{CYC}	D	System clock period	—	—	1 / f_{SYS}	ns
f_{LORL}	D	Loss of reference frequency window ⁽³⁾	Lower limit	1.6	3.7	MHz
f_{LORH}	D		Upper limit	24	56	
f_{SCM}	D	Self-clocked mode frequency ^{(4),(5)}	—	20	150	MHz
C_{JITTER}	T	CLKOUT period jitter ^{(6),(7),(8),(9)}	Short-term jitter ⁽¹⁰⁾	f_{SYS} maximum	-4	% f_{CLKOUT}
			Long-term jitter (average over 2 ms interval)	$f_{PLLIN} = 16$ MHz (resonator), f_{PLLCLK} at 64 MHz, 4000 cycles	—	10 ns
t_{PLL}	D	PLL lock time ^{(11), (12)}	—	—	200	μs
t_{dc}	D	Duty cycle of reference	—	40	60	%
f_{LCK}	D	Frequency LOCK range	—	-6	6	% f_{SYS}
f_{UL}	D	Frequency un-LOCK range	—	-18	18	% f_{SYS}
f_{CS}	D	Modulation depth	Center spread	±0.25	±4.0 (13)	% f_{SYS}
f_{DS}	D		Down spread	-0.5	-8.0	
f_{MOD}	D	Modulation frequency ⁽¹⁴⁾	—	—	70	kHz

1. $V_{DD_LV_CORx} = 1.2$ V ±10%; $V_{SS} = 0$ V; $T_A = -40$ to 125 °C, unless otherwise specified

2. Considering operation with PLL not bypassed.

3. "Loss of Reference Frequency" window is the reference frequency range outside of which the PLL is in self clocked mode.

4. Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls outside the f_{LOR} window.

5. f_{VCO} self clock range is 20–150 MHz. f_{SCM} represents f_{SYS} after PLL output divider (ERFD) of 2 through 16 in enhanced mode.

6. This value is determined by the crystal manufacturer and board design.

7. Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{SYS} . Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via $V_{DD_LV_COR0}$ and $V_{SS_LV_COR0}$ and variation in crystal oscillator frequency increase the C_{JITTER} percentage for a given interval.

8. Proper PC board layout procedures must be followed to achieve specifications.

9. Values are obtained with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of C_{JITTER} and either f_{CS} or f_{DS} (depending on whether center spread or down spread modulation is enabled).

10. Short term jitter is measured on the clock rising edge at cycle n and cycle n+4.

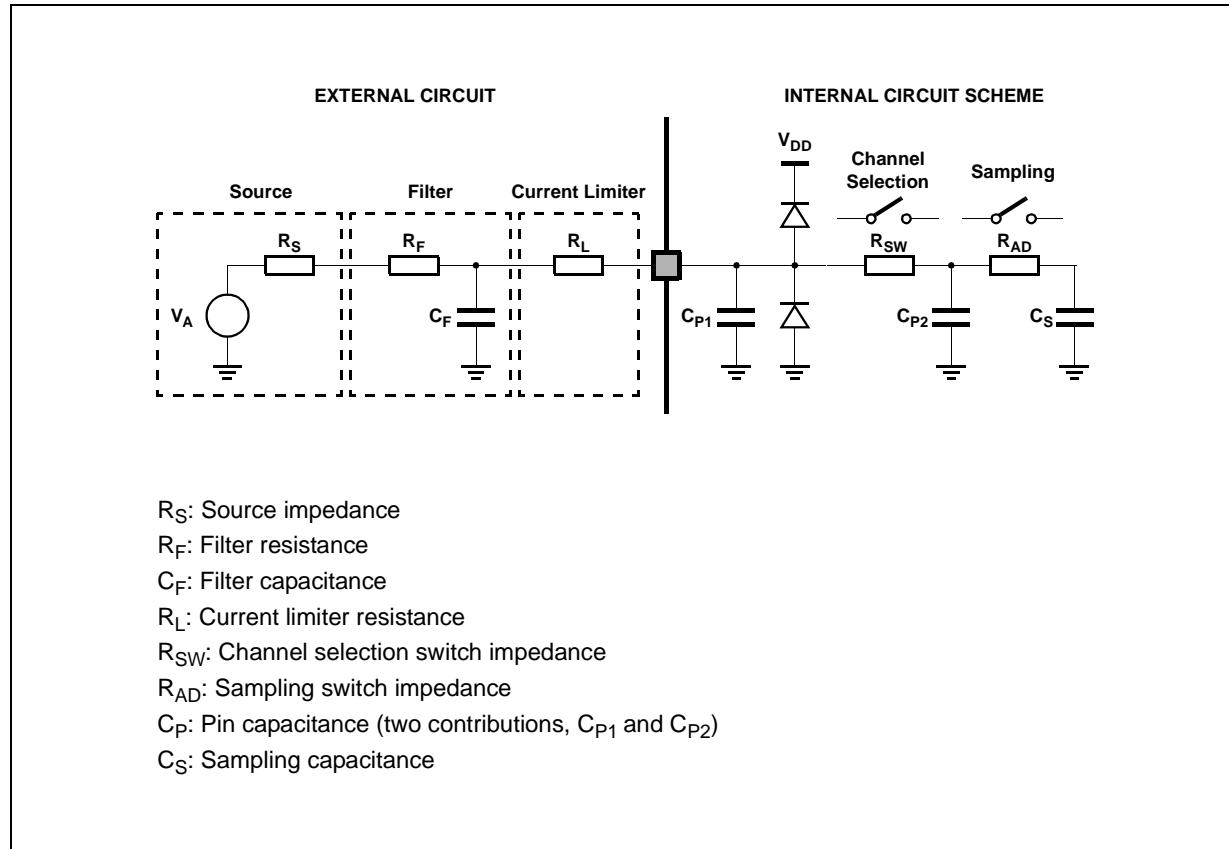
11. This value is determined by the crystal manufacturer and board design. For 4 MHz to 20 MHz crystals specified for this PLL, load capacitors should not exceed these limits.

12. This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).

13. This value is true when operating at frequencies above 60 MHz, otherwise f_{CS} is 2% (above 64 MHz).

14. Modulation depth will be attenuated from depth setting when operating at modulation frequencies above 50 kHz.

Figure 16. Input equivalent circuit



A second aspect involving the capacitance network shall be considered. Assuming the three capacitances C_F , C_{P1} and C_{P2} are initially charged at the source voltage V_A (refer to the equivalent circuit reported in Figure 16): A charge sharing phenomenon is installed when the sampling phase is started (A/D switch closed).

Figure 17. Transient behavior during sampling phase

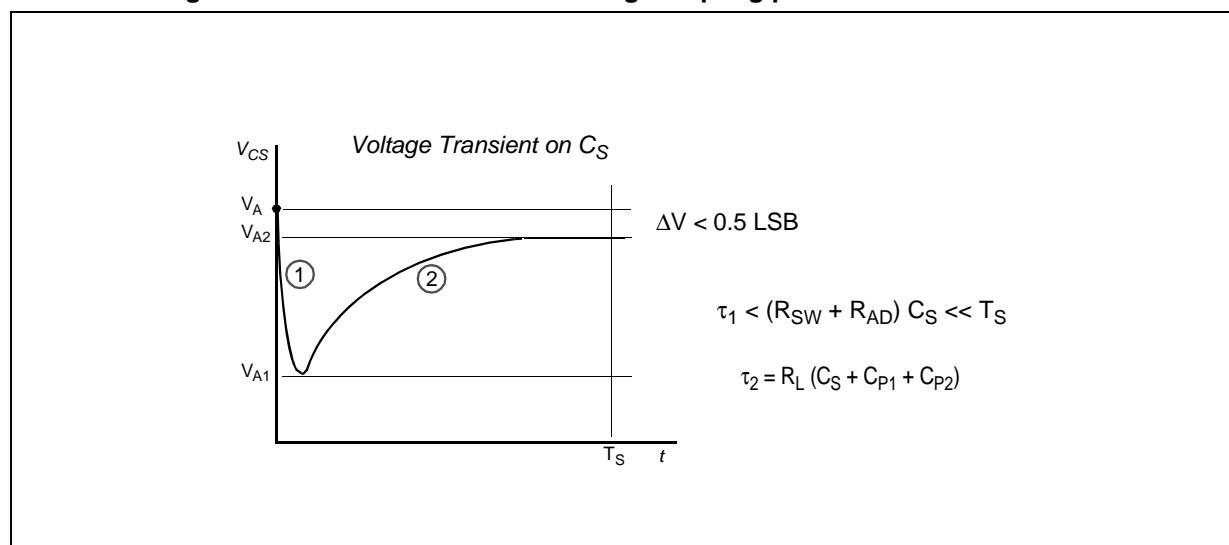


Table 37. RESET electrical characteristics

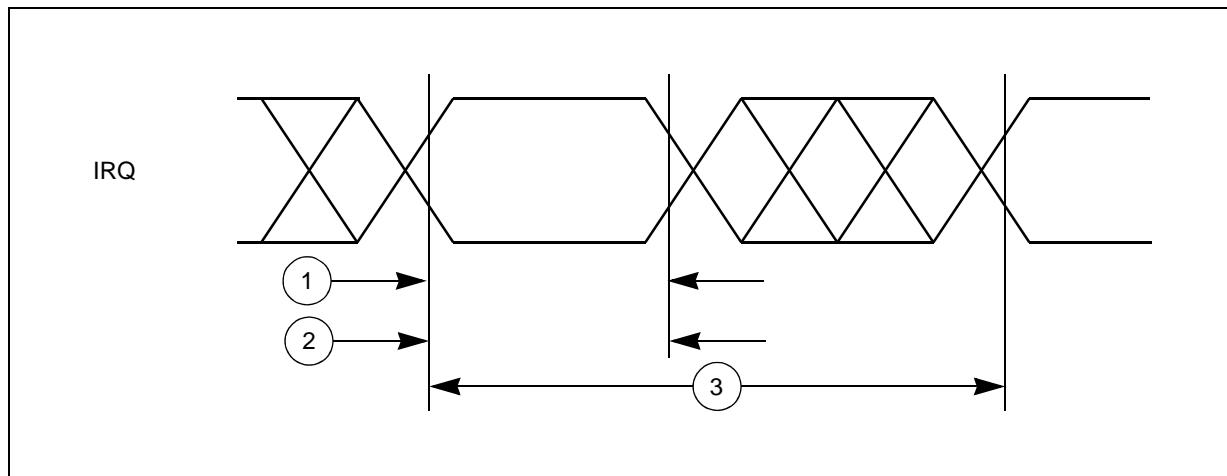
Symbol	C	Parameter	Conditions ⁽¹⁾	Value ⁽²⁾			Unit
				Min	Typ	Max	
V _{IH}	S R	P	Input high level CMOS (Schmitt Trigger)	—	0.65V _{DD}	—	V _{DD} + 0.4
V _{IL}	S R	P	Input low level CMOS (Schmitt Trigger)	—	-0.4	—	0.35V _{DD}
V _{HYS}	C C	C	Input hysteresis CMOS (Schmitt Trigger)	—	0.1V _{DD}	—	—
V _{OL}	C C	P	Output low level	Push Pull, I _{OL} = 2 mA, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	—	—	0.1V _{DD}
				Push Pull, I _{OL} = 1 mA, V _{DD} = 5.0 V ± 10%, PAD3V5V = 1 ⁽³⁾	—	—	0.1V _{DD}
				Push Pull, I _{OL} = 1 mA, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)	—	—	0.5
t _{tr}	C C	D	Output transition time output pin ⁽⁴⁾ MEDIUM configuration	C _L = 25 pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	10
				C _L = 50 pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	20
				C _L = 100 pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	40
				C _L = 25 pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	12
				C _L = 50 pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	25
				C _L = 100 pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	—	—	40
W _{FRST}	S R	P	RESET input filtered pulse	—	—	40	ns
W _{NFRST}	S R	P	RESET input not filtered pulse	—	500	—	—
t _{POR}	C C	D	Maximum delay before internal reset is released after all V _{DD_HV} reach nominal supply	Monotonic V _{DD_HV} supply ramp	—	—	1 ms
I _{WPUL}	C C	P	Weak pull-up current absolute value	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	10	—	150
				V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	10	—	150
				V _{DD} = 5.0 V ± 10%, PAD3V5V = 1 ⁽⁵⁾	10	—	250

1. V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = -40 to 125 °C, unless otherwise specified

2. All values need to be confirmed during device validation.

3. This is a transient configuration during power-up, up to the end of reset PHASE2 (refer to RGM module section of device reference manual).

Figure 28. External interrupt timing



3.17.5 DSPI timing

Table 41. DSPI timing⁽¹⁾

No.	Symbol	C	Parameter	Conditions	Value		Unit	
					Min	Max		
1	t_{SCK}	CC	D	DSPI cycle time	Master (MTFE = 0)	60	—	ns
					Slave (MTFE = 0)	60	—	
2	t_{CSC}	CC	D	CS to SCK delay	—	16	—	ns
3	t_{ASC}	CC	D	After SCK delay	—	26	—	ns
4	t_{SDC}	CC	D	SCK duty cycle	—	$0.4 * t_{SCK}$	$0.6 * t_{SCK}$	ns
5	t_A	CC	D	Slave access time	\overline{SS} active to SOUT valid	—	30	ns
6	t_{DIS}	CC	D	Slave SOUT disable time	\overline{SS} inactive to SOUT high impedance or invalid	—	16	ns
7	t_{PCSC}	CC	D	PCSx to \overline{PCSS} time	—	13	—	ns
8	t_{PASC}	CC	D	\overline{PCSS} to PCSx time	—	13	—	ns
9	t_{SUI}	CC	D	Data setup time for inputs	Master (MTFE = 0)	35	—	ns
					Slave	4	—	
					Master (MTFE = 1, CPHA = 0)	35	—	
					Master (MTFE = 1, CPHA = 1)	35	—	
10	t_{HI}	CC	D	Data hold time for inputs	Master (MTFE = 0)	-5	—	ns
					Slave	4	—	
					Master (MTFE = 1, CPHA = 0)	11	—	
					Master (MTFE = 1, CPHA = 1)	-5	—	

Table 43. LQFP64 package mechanical data (continued)

Symbol	Dimensions					
	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°
ccc ⁽²⁾	0.08			0.0031		

1. Values in inches are converted from millimeters (mm) and rounded to four decimal digits.

2. Tolerance

Table 45. Document revision history (continued)

Date	Revision	Changes
23-Dec-2010	3 (continued)	<p>Updated “Main oscillator electrical characteristics (5.0 V, NVUSRO[PAD3V5V] = 0)” table</p> <p>Updated “Main oscillator electrical characteristics (3.3 V, NVUSRO[PAD3V5V] = 1)” table</p> <p>“Input clock characteristics” table: updated f_{CLK} max value</p> <p>“PLLMRFM electrical specifications ($V_{DDPLL} = 1.08$ V to 1.32 V, $V_{SS} = V_{SSPLL} = 0$ V, $T_A = T_L$ to T_H)” table:</p> <ul style="list-style-type: none"> – Updated supply voltage range for V_{DDPLL} in the table title – Updated f_{SCM} max value – Updated C_{JITTER} row – Updated f_{MOD} max value <p>Updated “16 MHz RC oscillator electrical characteristics” table</p> <p>Updated “ADC conversion characteristics” table</p> <p>“Program and erase specifications” table:</p> <ul style="list-style-type: none"> – $T_{wprogram}$: updated initial max and max values – T_{BKPRG} 64 KB: updated initial max and max values – added information about “erase time” for Data Flash <p>“Flash module life” table:</p> <ul style="list-style-type: none"> – P/E, 32 KB: added typ value – P/E, 128 KB: added typ value <p>Replaced “Pad AC specifications (5.0 V, NVUSRO[PAD3V5V] = 0)” and “Pad AC specifications (3.3 V, INVUSRO[PAD3V5V] = 1)” tables with “Output pin transition times” table</p> <p>“JTAG pin AC electrical characteristics” table:</p> <ul style="list-style-type: none"> – t_{TDOV}: updated max value – t_{TDOHZ}: added min value and removed max value <p>“Nexus debug port timing” table: removed the rows “t_{MCYC}”, “t_{MDOV}”, “t_{MSEOV}”, and “t_{EVTOV}”</p> <p>Updated “External interrupt timing (IRQ pin)” table</p> <p>Updated “FlexCAN timing” table</p> <p>Updated “DSPI timing” table</p> <p>Updated “Ordering information” section</p>

Table 45. Document revision history (continued)

Date	Revision	Changes
13-May-2011	4	<p>Editorial and formatting changes throughout</p> <p>Cover page features list:</p> <ul style="list-style-type: none"> • changed core feature "64 MHz" to "Up to 64 MHz" • changed Data flash memory "64 (4 × 16) KB" to "Additional 64 (4 × 16) KB" • changed "1 FlexCAN interface" to "Up to 2 FlexCAN interface" <p>Updated Device summary</p> <p>Section "Introduction": Reorganized contents</p> <p>SPC560P40 device configuration differences: Editorial changes to indicate that the table concerns only the SPC560P40 devices); removed "DSPI" row</p> <p>Block diagram (SPC560P40 full-featured configuration): reorganized blocks above and below peripheral bridge; made arrow going from peripheral bridge to crossbar switch bidirectional; removed SPC560P34 part number from title</p> <p>Added section "Features details"</p> <p>64-pin and 100-pin LQFP pinout diagrams: replaced instances of HV_ADO with HV_ADC0</p> <p>System pins: updated "XTAL" and "EXTAL" rows</p> <p>Updated LQFP thermal characteristics</p> <p>Updated EMI testing specifications</p> <p>section "Voltage regulator electrical characteristics": removed BCP56 from named BJTs; replaced two configuration diagrams and two electrical characteristics tables with single diagram and single table</p> <p>Voltage regulator electrical characteristics: updated $V_{DD_LV_REGCOR}$ row</p> <p>Low voltage monitor electrical characteristics: updated $V_{MLVDDOK_H}$ max value—was 1.15 V; is 1.145 V</p> <p>Supply current (5.0 V, NVUSRO[PAD3V5V] = 0): changed symbol $I_{DD_LV_CORE}$ to $I_{DD_LV_CORx}$; changed parameter classification from T to P for $I_{DD_LV_CORx}$ RUN—Maximum mode at 64 MHz; added I_{DD_FLASH} characteristics; replaced instances of "Airbag" mode with "Typical mode"</p> <p>Supply current (3.3 V, NVUSRO[PAD3V5V] = 1): changed symbol $I_{DD_LV_CORE}$ to $I_{DD_LV_CORx}$; replaced instances of "Airbag" mode with "Typical mode"</p> <p>DC electrical characteristics (3.3 V, NVUSRO[PAD3V5V] = 1): corrected parameter description for V_{OL_F}—was "Fast, high level output voltage"; is "Fast, low level output voltage"</p> <p>Added <i>Section 3.10.4, Input DC electrical characteristics definition</i></p> <p>Main oscillator output electrical characteristics tables: replaced instances of EXTAL with XTAL; added load capacitance parameter</p> <p>FMPPLL electrical characteristics: updated conditions and table title; removed f_{sys} row; updated $f_{FMPPLLOUT}$ values; replaced instances of V_{DDPLL} with $V_{DD_LV_COR0}$; replaced instances of V_{SSPLL} with $V_{SS_LV_COR0}$</p> <p>16 MHz RC oscillator electrical characteristics: removed rows $\Delta_{RCMTRIM}$ and $\Delta_{RCMSTEP}$</p> <p>ADC characteristics and error definitions: updated symbols</p> <p>ADC conversion characteristics: updated symbols; added row t_{ADC_PU}</p> <p>Added <i>Section 3.15.2, Flash memory power supply DC characteristics</i></p> <p>Added <i>Section 3.15.3, Start-up/Switch-off timings</i></p> <p>Removed section "Generic timing diagrams"</p> <p>Updated Start-up reset requirements diagram</p> <p>Removed FlexCAN timing characteristics</p> <p>RESET electrical characteristics: added row for t_{POR}</p> <p>In the range of figures "DSPI Classic SPI Timing — Master, CPHA = 0" to "DSPI PCS Strobe (PCSS) Timing": added note</p> <p>Updated Order codes</p>